

QUALIFICATION RESULT SUMMARY

SOICn package at ASE Chungli (AET)

	STRESS TESTS and CONDITIONS					
	Highly Accelerated Stress Test (HAST)*	Temperature Cycle (TC)*	Autoclave (AC)*	Solder Heat Resistance (SHR)*	High Temperature Storage (HTS)	Field Induced Charged Device Model (FICDM)
	JEDEC <i>JESD22-A110</i>	JEDEC <i>JESD22-A104</i>	JEDEC <i>JESD22-A102</i>	<i>ADI-0049</i>	JEDEC <i>JESD22-A103</i>	JEDEC <i>JESD22-C101</i>
Qual Vehicle 1	PASS	PASS	PASS	PASS	PASS	PASS ±1250V
Qual Vehicle 2	PASS	PASS	PASS	PASS	PASS	PASS ±1250V
TOTAL:	0 / 462	0 / 462	0 / 462	0 / 66	0 / 149	-

*These samples were subjected to preconditioning (per J-STD-020 Level 1) prior to the start of the stress test. Level 1 preconditioning consists of the following: Bake: 24 hrs @ 125°C, Soak: Unbiased Soak: 168 hrs @ 85°C, 85%RH, Reflow: 3 passes through an oven with a peak temperature of 260°C.